

# SCHOTTKY DIODE. KDN-30040.

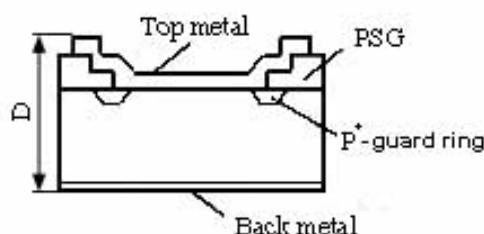
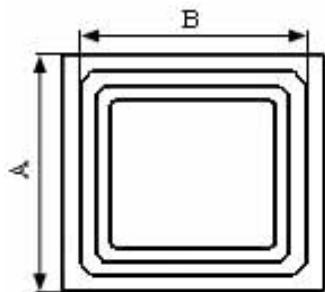
Rev.1. Feb. 2010



**VSP-MIKRON**

**30A/40V. Die Size-106\*158mil.**

Electrical Characteristics	Symbol	Unit	Spec. Limit	Die Sort
Breakdown Voltage @ $I_R=10\text{mA}$	$V_{BR}$	V	40	45
Average Rectified Forward Current	$I_{F(AV)}$	A	30,0	-
DC Forward Voltage @ $25^\circ\text{C}$ , $I_F=30,0\text{A}$	$V_F$	V	0,57	0,55
Maximum Reverse Current  @ $25^\circ\text{C}$ , $V_R=45\text{V}$ $25^\circ\text{C}$ , $V_R=40\text{V}$ $125^\circ\text{C}$ , $V_R=40\text{V}$	$I_R$	mA	- 0,80 0,50 350	0,80 0,50 300,0
Peak Forward Surge Current 8,3ms single half sine-wave superimposed on rated load (JEDEC METHOD)	$I_{FSM}$	A	300	-
Peak Repetitive Reverse Surge Current @ $2,0\mu\text{s}$ , $f=1\text{kHz.}$ , $T_J<150^\circ\text{C.}$	$I_{RRM}$	A	5,0	
Electrostatic Discharge Voltage. JEDEC Method. ESD HBM. Contact.	ESD	kV	$\pm 8$ (contact)	
Voltage Rate of Change	$dV/dt$	V/ $\mu\text{S}$	10.000	
Operating Junction Temperature	$T_J$	$^\circ\text{C}$	150	



DIM	ITEM	$\mu\text{m}$
$A_x$ $A_y$	Wafer Form Die Size	2700 4000
$B_x$ $B_y$	Top Metal Size	2560 3860
D	Thickness	350max
Scribe line Width		80

Top metal: a) Ti-Ni-Ag – for Soldering;  
b) Al.- for Wire Bonding.  
Back metal: Ti-Ni-Ag.